

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. : <u>ST 9903a</u>	SERIAL NO. <u>09/890,656</u>
		APPLICANT : <u>Reinhard Schauer et al.</u>	
		FILING DATE: <u>August 2, 2001</u>	GROUP: <u>2811</u>

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TT	AA	5,935,320	8/10/99	Graef et al.	—	—	
	AB						
	AC						
	AD						
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	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
TT	AL	0725 169	8/7/96	Europe	—	—		
TT	AM	19823962	12/2/99	Germany	—	—		
TT	AN	0959 154	11/24/99	Europe	—	—		
TT	AO	0644 588	3/22/95	Europe	—	—		
TT	AP	0829 559	12/15/99	Europe	—	—		

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

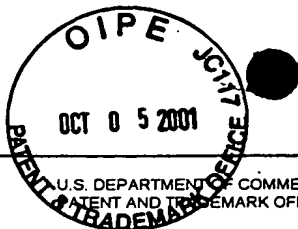
TT	AR		Electrochemical Society Proceedings, vol. 98-1, pp. 855-861
TT	AS		Jpn. J. Appl. Phys., Vol. 36, 1997, pp. 2565-2570
TT	AT		English Derwent Abstract AN 1996-356122 corresponding to EPO 725 169

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TT	AR		English Derwent Abstract AN 2000-024759
			corresponding to DE 198 23 962
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			pp. 1775-1777
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			Soc., 1973, vol. 120, pp. 116-122

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	AS		Ohshita, Y. et al; Journal of Crystal Growth, 1991, vol. 108, pp. 499-507
	AT		Hammond, M.L.; Silicon Epitaxy, Solid State Technology, 1978, H. 11, pp. 68-75

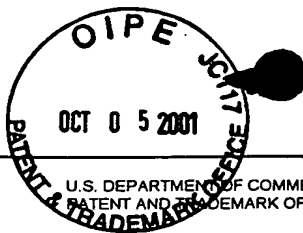
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TT	AR		Bloem J. and Chassen, W.A.P.; Philips Tech. Rev.,
			1983/84, vol. 41, no. 2, pp. 60-69
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